

An implementation of XDS integration for DIALS

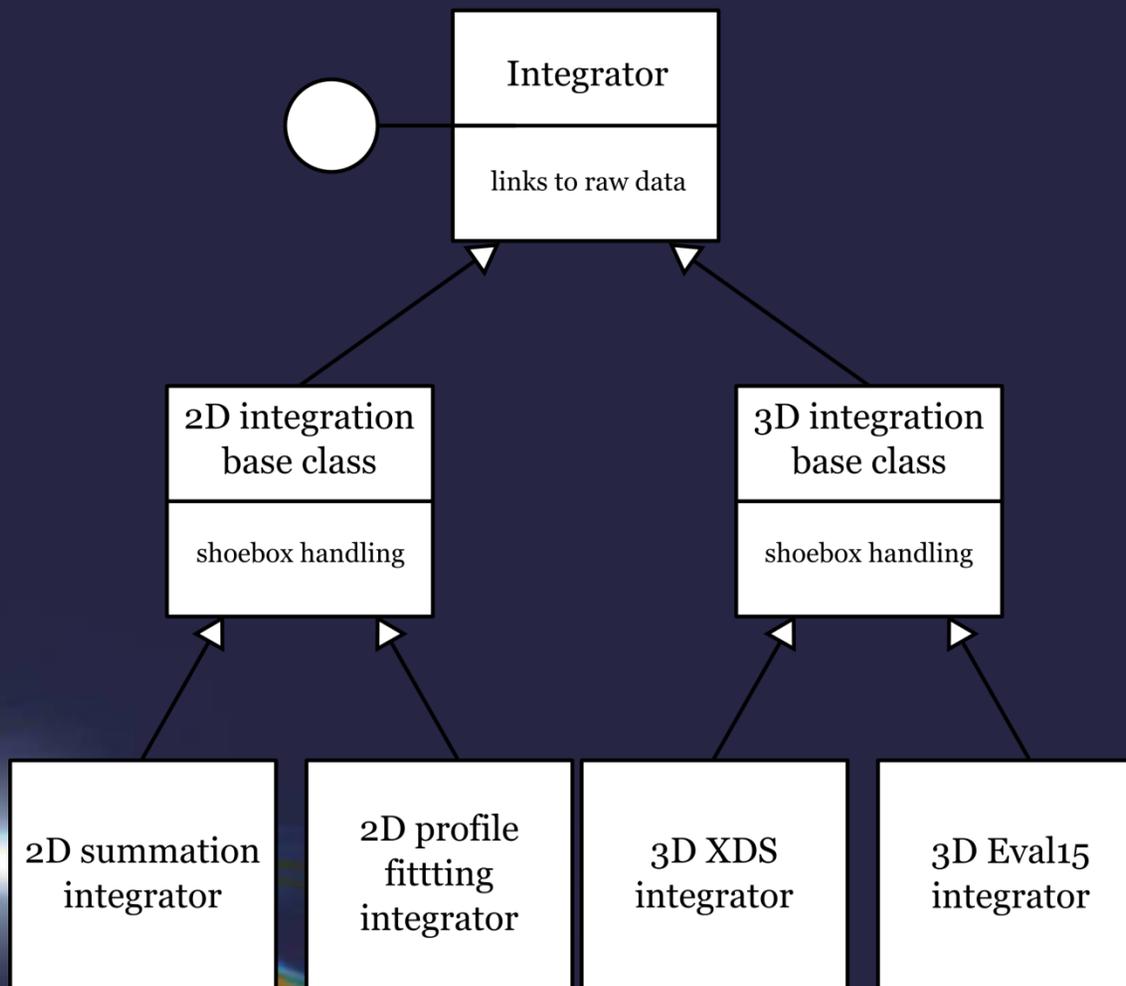
James Parkhurst



Design principles (interfaces)

Integrator hierarchy

See Graeme Winter's talk



diamond

XDS

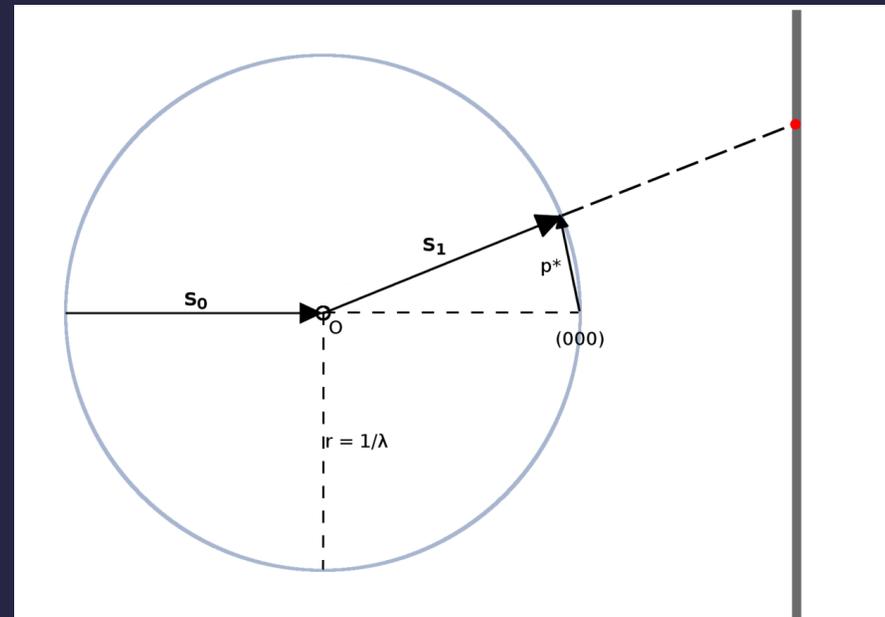
- Program for processing single-crystal monochromatic diffraction data recorded by the rotation method
- Differs from other 2D integration programs such as Mosflm by integrating reflection profiles in 3D
- Described in Kabsch, W. (2010). Integration, scaling, space-group assignment and post-refinement. *Acta Crystallographica Section D Biological Crystallography*, 66(Pt 2), 133–44.

Overview

- Modeling rotation images
 - Spot prediction
 - Localizing diffraction spots
 - Basis extraction
 - Indexing
 - Refinement
- Integration
 - Reflection mask
 - Background subtraction
 - Reciprocal space transform
 - Intensity Estimation

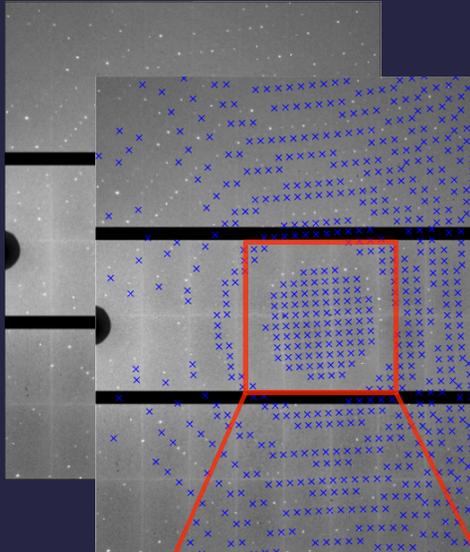
Spot prediction: method

- Purpose: To obtain detector coordinates and rotation angles for each predicted reflection
- Generate observable miller indices
- For each index calculate:
 - intersection angle with Ewald sphere
 - diffracted beam vector
 - intersection point of diffracted beam vector with detector plane

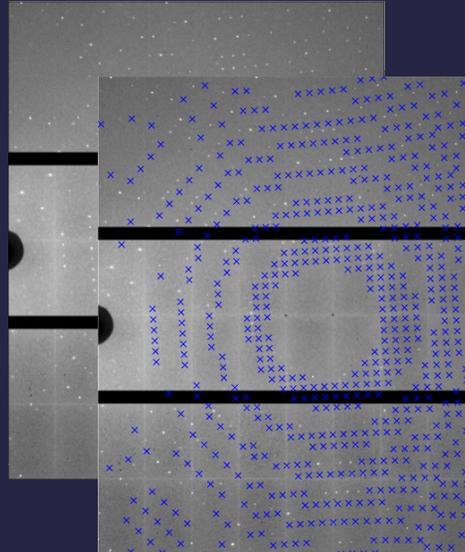


Spot prediction: results

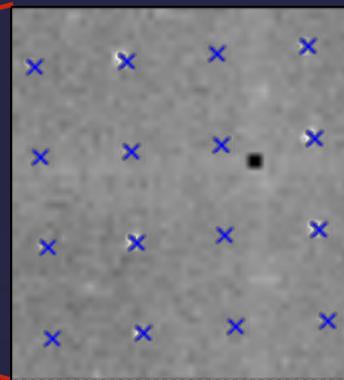
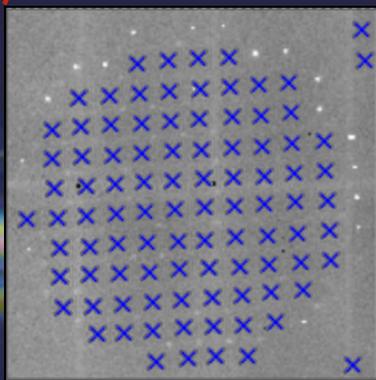
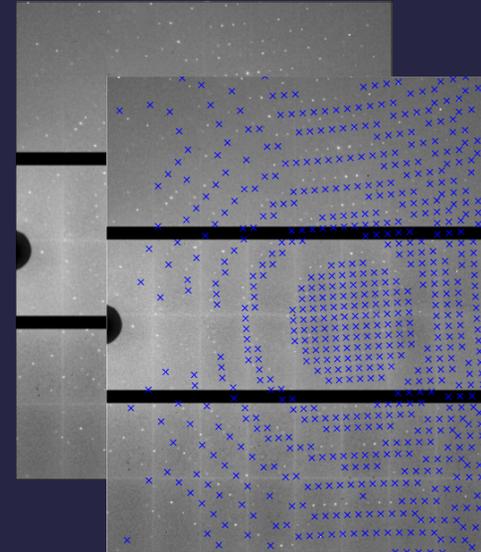
$\varphi = \varphi_0; z = 0$



$\varphi = \varphi_1; z = 1$



$\varphi = \varphi_2; z = 2$



Spot positions validated to within 0.1 pixels w.r.t refined XDS spot positions

Reciprocal space transform: coordinate system

Definition:

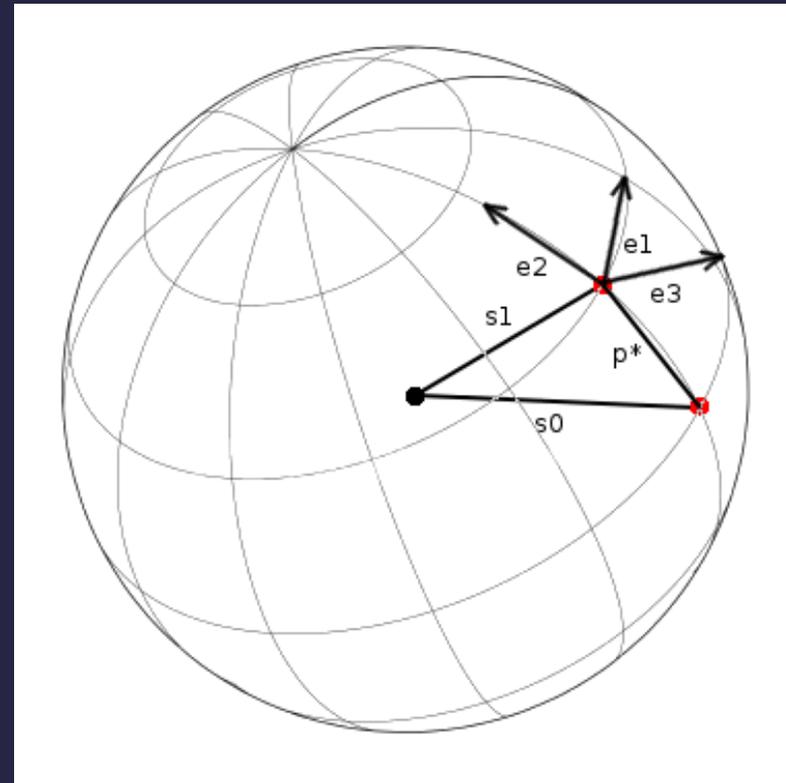
$$e_1 = \mathbf{s}_1 \times \mathbf{s}_0 / |\mathbf{s}_1 \times \mathbf{s}_0|$$

$$e_2 = \mathbf{s}_1 \times e_1 / |\mathbf{s}_1 \times e_1|$$

$$e_3 = \mathbf{s}_1 + \mathbf{s}_0 / |\mathbf{s}_1 + \mathbf{s}_0|$$

Motivation:

- Rotation about a fixed axis leads to an increase in the path length through the Ewald sphere.
- Transformed reflections have a standard shape and appear to have followed the shortest path through the Ewald sphere.



Reciprocal space transform: mapping

Formula

$$\varepsilon_1 = e_1 \cdot \frac{(S' - S_1)}{|S_1|} \times \frac{180}{\pi} \quad \varepsilon_2 = e_2 \cdot \frac{(S' - S_1)}{|S_1|} \times \frac{180}{\pi}$$

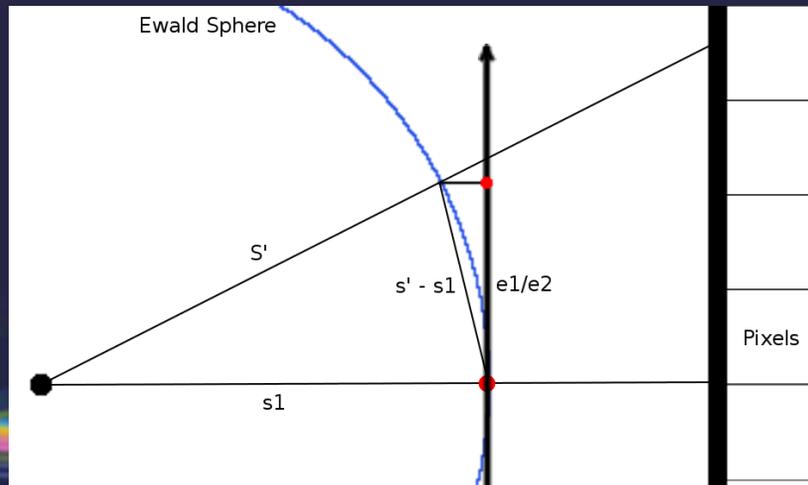
$$\varepsilon_3 = e_3 \cdot \frac{[R(\mathbf{m}_2, \varphi' - \varphi)\mathbf{p}^* - \mathbf{p}^*]}{|\mathbf{p}^*|} \times \frac{180}{\pi} \approx \zeta \cdot (\varphi' - \varphi)$$

ζ is related to the inverse Lorentz correction factor.

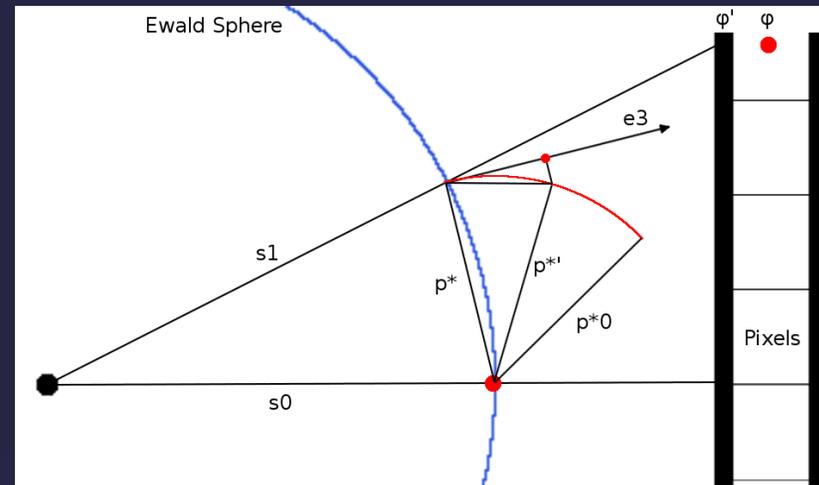
$$\zeta = \mathbf{m}_2 \cdot \mathbf{e}_1$$

$$L^{-1} = \frac{|\mathbf{m}_2 \cdot (\mathbf{S}_1 \times \mathbf{S}_0)|}{|\mathbf{S}_1||\mathbf{S}_0|} = |\zeta \sin \angle(\mathbf{S}_1, \mathbf{S}_0)|$$

e_1/e_2 transform



e_3 transform



Reciprocal space transform: required steps

Calculate reflection mask



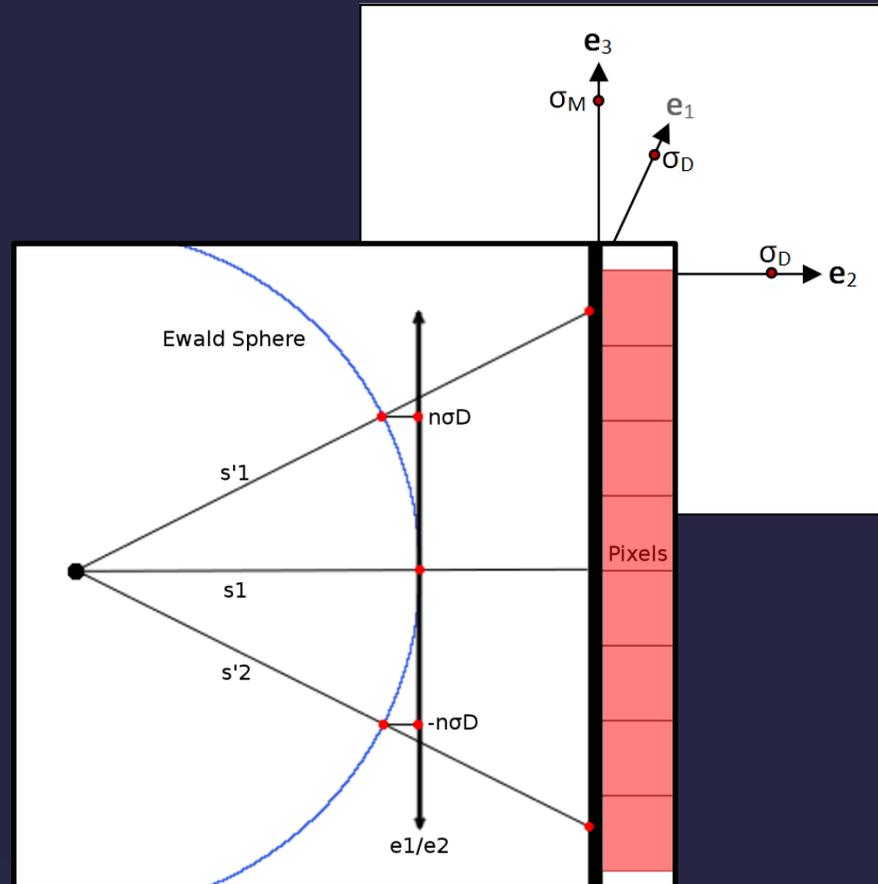
Subtract background intensity



Perform reciprocal space transform

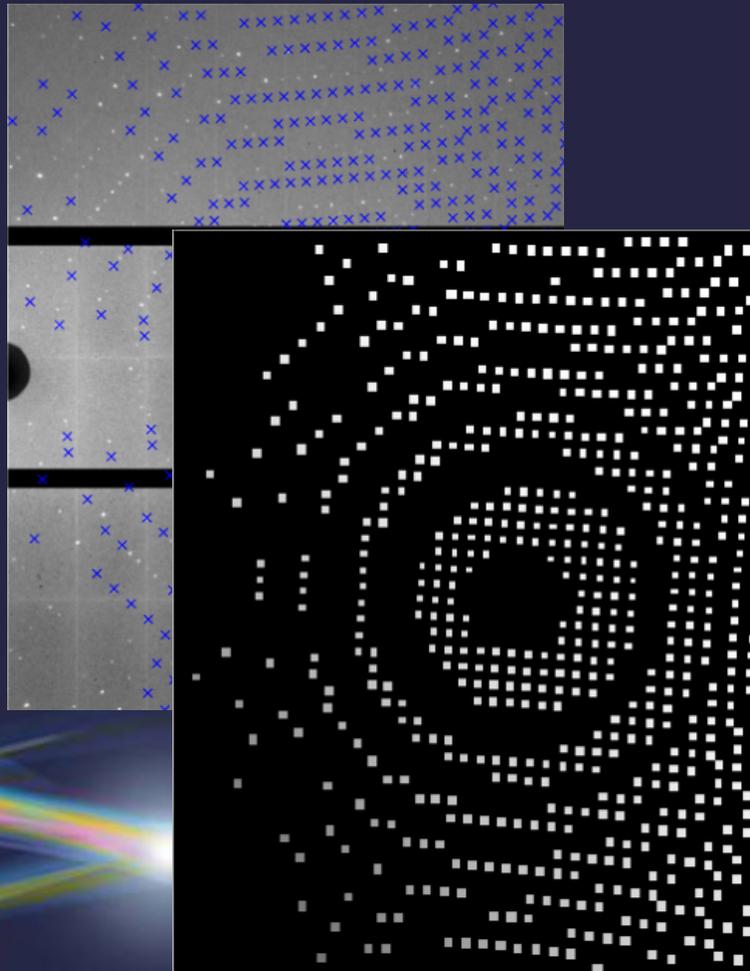
Reflection mask: calculating the shoebox

- Reflection mask uses standard deviation of beam divergence (σ_D) and mosaicity (σ_M) in reciprocal space to set shoebox around each reflection
- shoebox $\leq |\sigma_D|e_1, |\sigma_D|e_2, |\sigma_M|e_3$
- Detector coordinates and rotation angles at limits are calculated to obtain shoebox in detector space
- Results in shoebox specific to each reflection

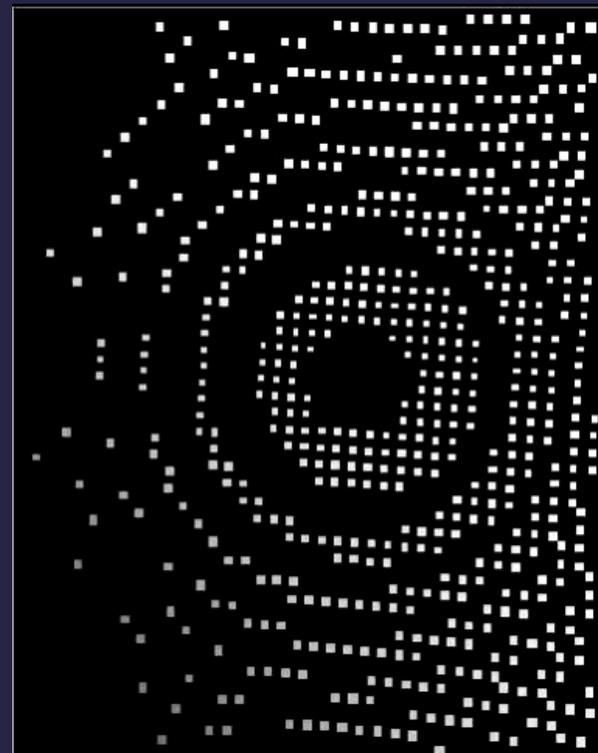


Reflection mask: images

Single frame:

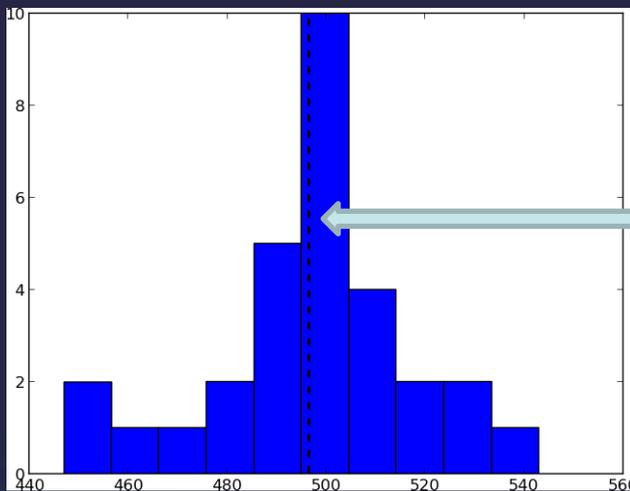


Whole dataset:



Background subtraction: method

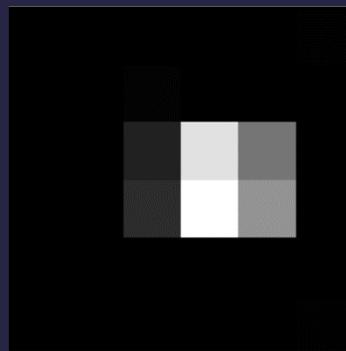
- Assume enough pixels available (> 10) to calculate background
- Assume background intensity distributed normally
- Remove high intensity pixels, one at a time, until intensity is normally distributed
- Select mean of remaining pixels as background intensity



Background
intensity value

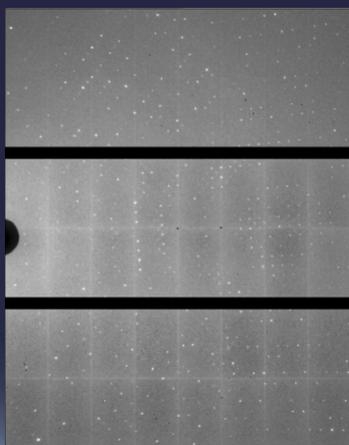
Background subtraction: results

Single spot:



Whole dataset

Whole frame:



Reciprocal space transform: gridding frames

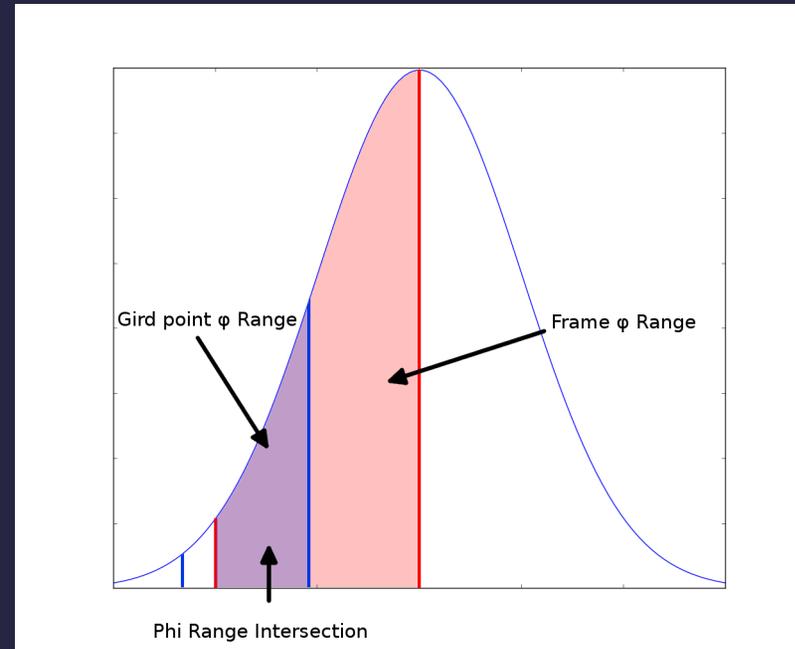
- Assume Gaussian spot profiles along e_3
- Integrate over range of ϕ for the image frame, j :

$$I_j = \int_{\Gamma_j} \exp(-(\phi' - \phi)^2 / 2\sigma^2) d\phi'$$

- Integrate over the intersection of the range of phi range of the grid point v_3 , and image frame, j :

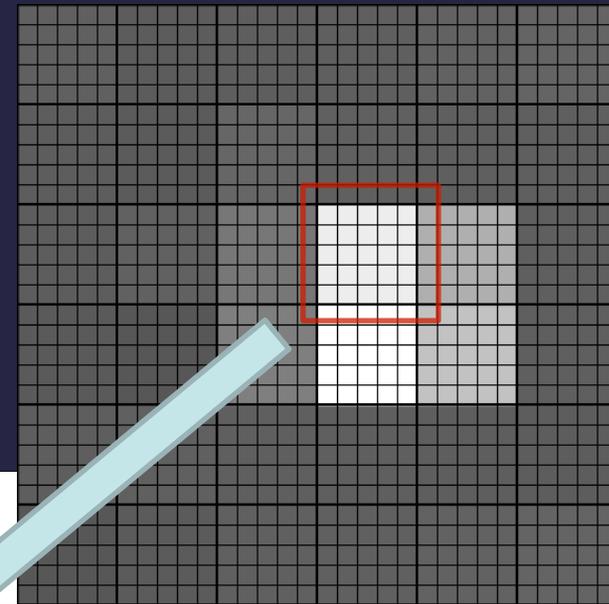
$$I_{v_3j} = \int_{\Gamma_j \cap \Gamma_{v_3}} \exp(-(\phi' - \phi)^2 / 2\sigma^2) d\phi'$$

- Fraction of intensity contributed by image frame, j to grid coordinate, v_3 is: $\frac{I_{v_3j}}{I_j}$

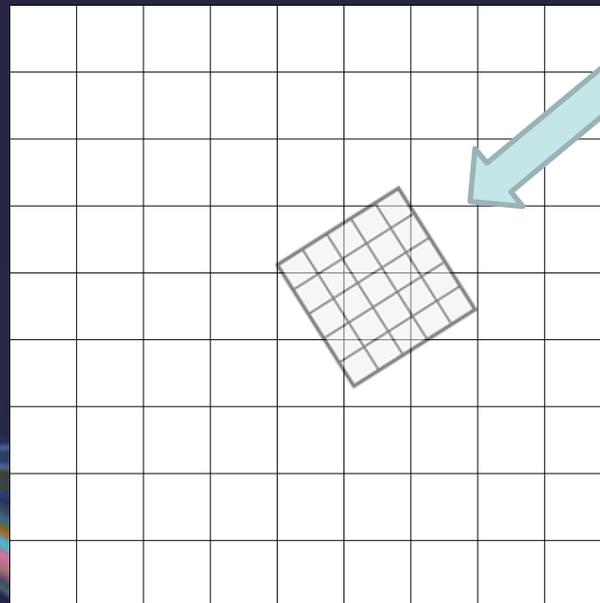


Reciprocal space transform: gridding pixels

- Assumes flat distribution of intensity over pixel area
- Pixels sub-divided into 5x5 equal areas
- $1/25$ intensity is given to transformed grid point



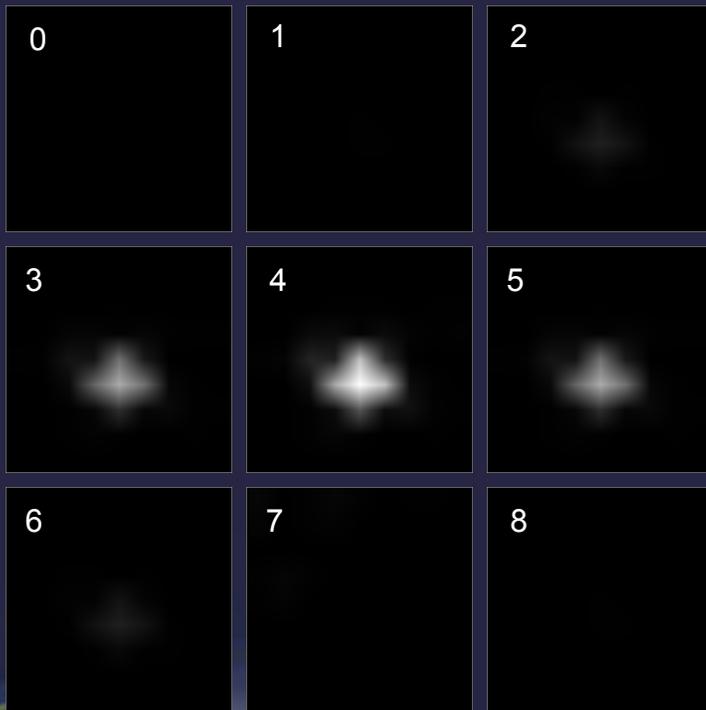
Detector image



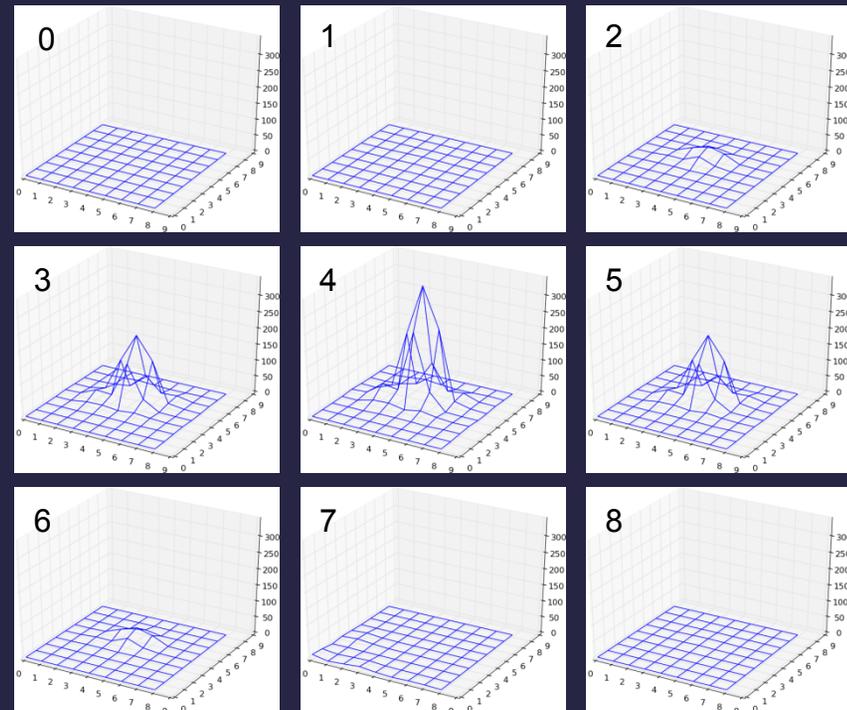
Reciprocal space transform grid

Transformed reflection profiles

2D

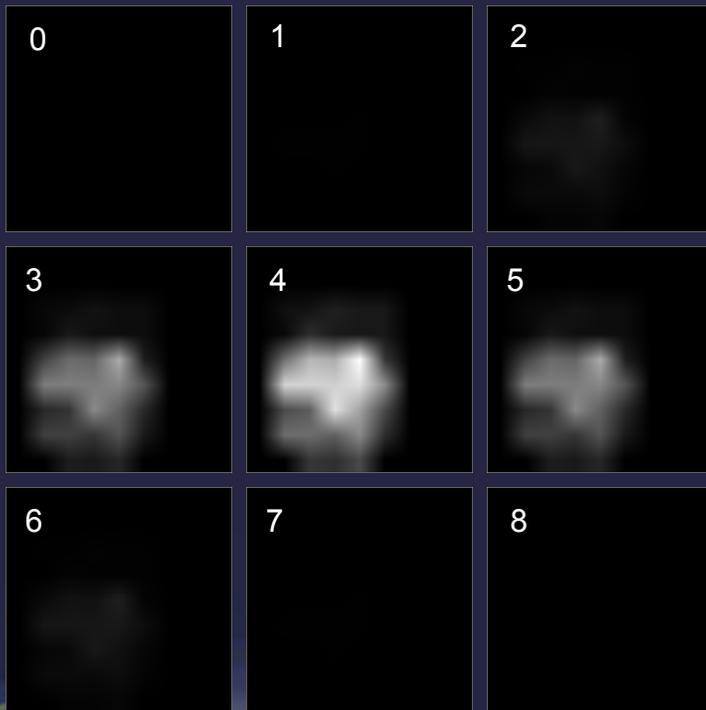


3D

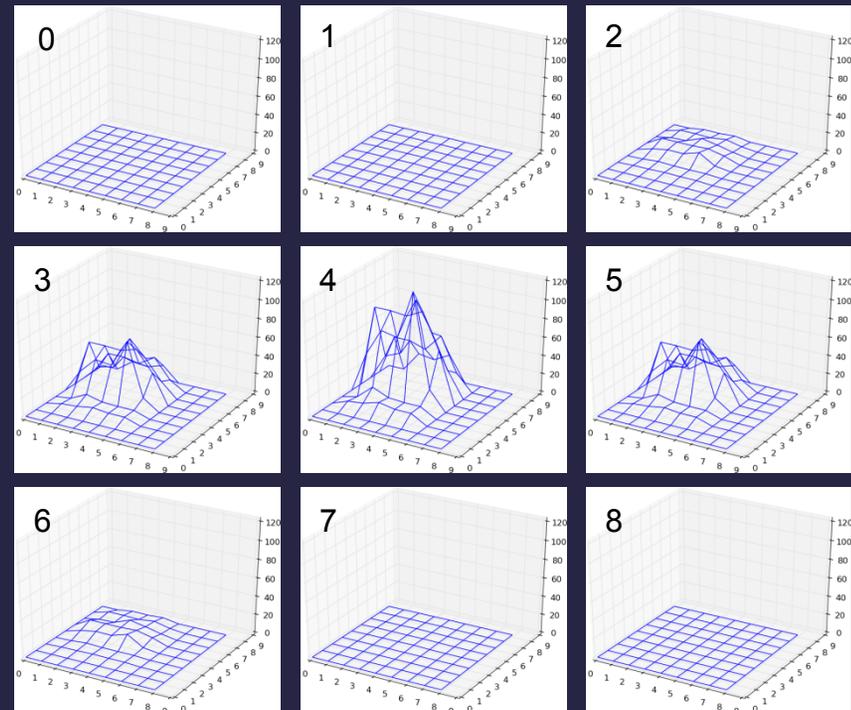


Transformed reflection profiles

2D



3D



Summary

- Implemented XDS algorithms for:
 - spot prediction
 - reflection mask calculation
 - background subtraction
 - reciprocal space transform
- Further work:
 - algorithms basically work but need to be rigorously tested
 - implementation of 'missing' XDS algorithms

Questions?

